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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	5184
Number of Logic Elements/Cells	51840
Total RAM Bits	442368
Number of I/O	808
Number of Gates	2392000
Voltage - Supply	1.71V ~ 1.89V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/ep20k1500efc33-1x">https://www.e-xfl.com/product-detail/intel/ep20k1500efc33-1x</a>

Windows-based PCs, Sun SPARCstations, and HP 9000 Series 700/800 workstations

- Altera MegaCore® functions and Altera Megafunction Partners Program (AMPP<sup>SM</sup>) megafunctions
- NativeLink™ integration with popular synthesis, simulation, and timing analysis tools
- Quartus II SignalTap® embedded logic analyzer simplifies in-system design evaluation by giving access to internal nodes during device operation
- Supports popular revision-control software packages including PVCS, Revision Control System (RCS), and Source Code Control System (SCCS)

**Table 4. APEX 20K QFP, BGA & PGA Package Options & I/O Count** *Notes (1), (2)*

Device	144-Pin TQFP	208-Pin PQFP RQFP	240-Pin PQFP RQFP	356-Pin BGA	652-Pin BGA	655-Pin PGA
EP20K30E	92	125				
EP20K60E	92	148	151	196		
EP20K100	101	159	189	252		
EP20K100E	92	151	183	246		
EP20K160E	88	143	175	271		
EP20K200		144	174	277		
EP20K200E		136	168	271	376	
EP20K300E			152		408	
EP20K400					502	502
EP20K400E					488	
EP20K600E					488	
EP20K1000E					488	
EP20K1500E					488	

## General Description

APEX™ 20K devices are the first PLDs designed with the MultiCore architecture, which combines the strengths of LUT-based and product-term-based devices with an enhanced memory structure. LUT-based logic provides optimized performance and efficiency for data-path, register-intensive, mathematical, or digital signal processing (DSP) designs. Product-term-based logic is optimized for complex combinatorial paths, such as complex state machines. LUT- and product-term-based logic combined with memory functions and a wide variety of MegaCore and AMPP functions make the APEX 20K device architecture uniquely suited for system-on-a-programmable-chip designs. Applications historically requiring a combination of LUT-, product-term-, and memory-based devices can now be integrated into one APEX 20K device.

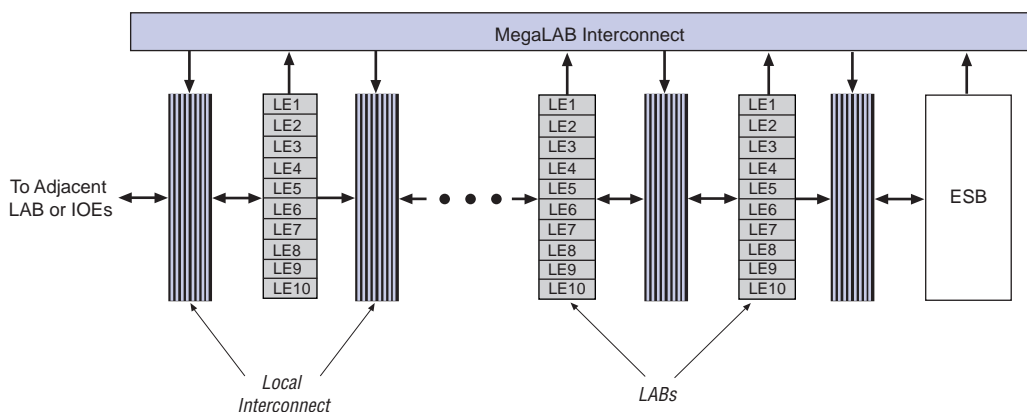
APEX 20KE devices are a superset of APEX 20K devices and include additional features such as advanced I/O standard support, CAM, additional global clocks, and enhanced ClockLock clock circuitry. In addition, APEX 20KE devices extend the APEX 20K family to 1.5 million gates. APEX 20KE devices are denoted with an “E” suffix in the device name (e.g., the EP20K1000E device is an APEX 20KE device). [Table 8](#) compares the features included in APEX 20K and APEX 20KE devices.

APEX 20K devices provide two dedicated clock pins and four dedicated input pins that drive register control inputs. These signals ensure efficient distribution of high-speed, low-skew control signals. These signals use dedicated routing channels to provide short delays and low skews. Four of the dedicated inputs drive four global signals. These four global signals can also be driven by internal logic, providing an ideal solution for a clock divider or internally generated asynchronous clear signals with high fan-out. The dedicated clock pins featured on the APEX 20K devices can also feed logic. The devices also feature ClockLock and ClockBoost clock management circuitry. APEX 20KE devices provide two additional dedicated clock pins, for a total of four dedicated clock pins.

## MegaLAB Structure

APEX 20K devices are constructed from a series of MegaLAB™ structures. Each MegaLAB structure contains a group of logic array blocks (LABs), one ESB, and a MegaLAB interconnect, which routes signals within the MegaLAB structure. The EP20K30E device has 10 LABs, EP20K60E through EP20K600E devices have 16 LABs, and the EP20K1000E and EP20K1500E devices have 24 LABs. Signals are routed between MegaLAB structures and I/O pins via the FastTrack Interconnect. In addition, edge LABs can be driven by I/O pins through the local interconnect. Figure 2 shows the MegaLAB structure.

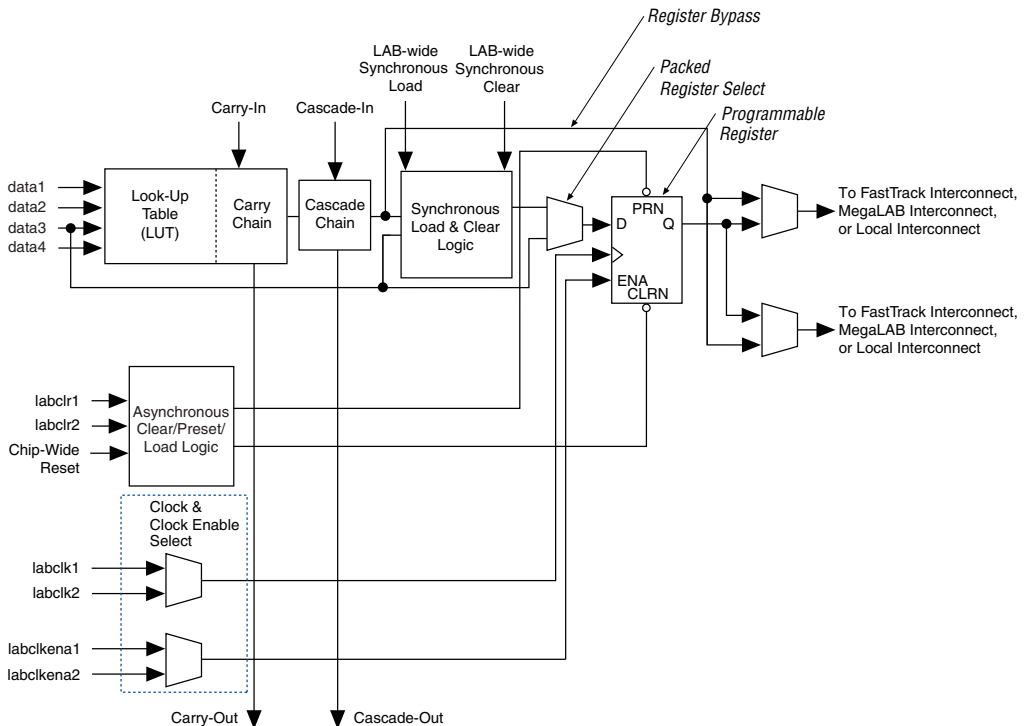
**Figure 2. MegaLAB Structure**



## Logic Element

The LE, the smallest unit of logic in the APEX 20K architecture, is compact and provides efficient logic usage. Each LE contains a four-input LUT, which is a function generator that can quickly implement any function of four variables. In addition, each LE contains a programmable register and carry and cascade chains. Each LE drives the local interconnect, MegaLAB interconnect, and FastTrack Interconnect routing structures. See [Figure 5](#).

**Figure 5. APEX 20K Logic Element**



Each LE's programmable register can be configured for D, T, JK, or SR operation. The register's clock and clear control signals can be driven by global signals, general-purpose I/O pins, or any internal logic. For combinatorial functions, the register is bypassed and the output of the LUT drives the outputs of the LE.

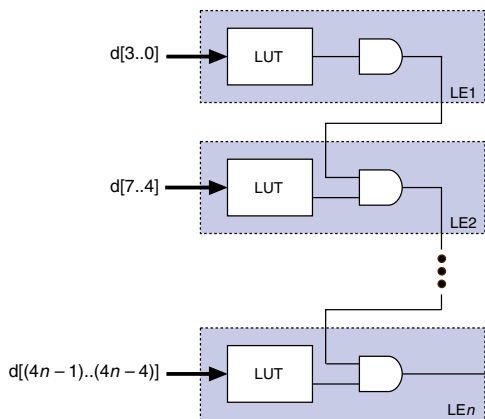
## Cascade Chain

With the cascade chain, the APEX 20K architecture can implement functions with a very wide fan-in. Adjacent LUTs can compute portions of a function in parallel; the cascade chain serially connects the intermediate values. The cascade chain can use a logical AND or logical OR (via De Morgan's inversion) to connect the outputs of adjacent LEs. Each additional LE provides four more inputs to the effective width of a function, with a short cascade delay. Cascade chain logic can be created automatically by the Quartus II software Compiler during design processing, or manually by the designer during design entry.

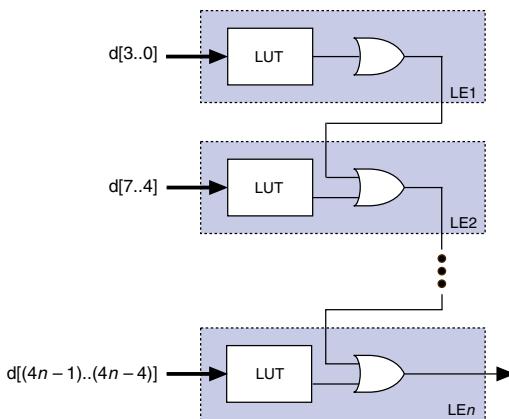
Cascade chains longer than ten LEs are implemented automatically by linking LABs together. For enhanced fitting, a long cascade chain skips alternate LABs in a MegaLAB structure. A cascade chain longer than one LAB skips either from an even-numbered LAB to the next even-numbered LAB, or from an odd-numbered LAB to the next odd-numbered LAB. For example, the last LE of the first LAB in the upper-left MegaLAB structure carries to the first LE of the third LAB in the MegaLAB structure. Figure 7 shows how the cascade function can connect adjacent LEs to form functions with a wide fan-in.

**Figure 7. APEX 20K Cascade Chain**

**AND Cascade Chain**



**OR Cascade Chain**



### Normal Mode

The normal mode is suitable for general logic applications, combinatorial functions, or wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in are inputs to a four-input LUT. The Quartus II software Compiler automatically selects the carry-in or the DATA3 signal as one of the inputs to the LUT. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. LEs in normal mode support packed registers.

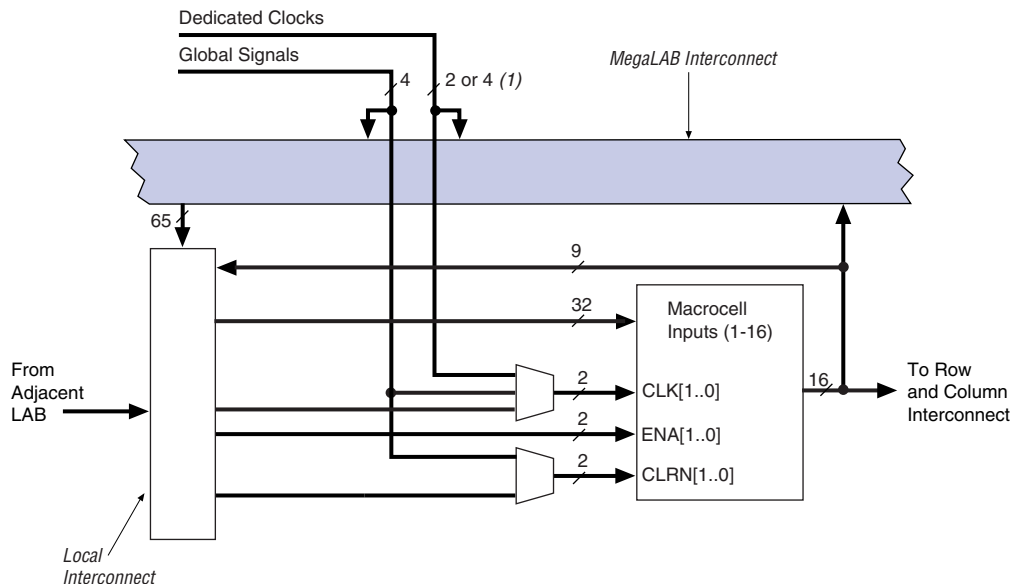
### Arithmetic Mode

The arithmetic mode is ideal for implementing adders, accumulators, and comparators. An LE in arithmetic mode uses two 3-input LUTs. One LUT computes a three-input function; the other generates a carry output. As shown in [Figure 8](#), the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, when implementing an adder, this output is the sum of three signals: DATA1, DATA2, and carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports simultaneous use of the cascade chain. LEs in arithmetic mode can drive out registered and unregistered versions of the LUT output.

The Quartus II software implements parameterized functions that use the arithmetic mode automatically where appropriate; the designer does not need to specify how the carry chain will be used.

### Counter Mode

The counter mode offers clock enable, counter enable, synchronous up/down control, synchronous clear, and synchronous load options. The counter enable and synchronous up/down control signals are generated from the data inputs of the LAB local interconnect. The synchronous clear and synchronous load options are LAB-wide signals that affect all registers in the LAB. Consequently, if any of the LEs in an LAB use the counter mode, other LEs in that LAB must be used as part of the same counter or be used for a combinatorial function. The Quartus II software automatically places any registers that are not used by the counter into other LABs.

**Figure 13. Product-Term Logic in ESB**

**Note to Figure 13:**

(1) APEX 20KE devices have four dedicated clocks.

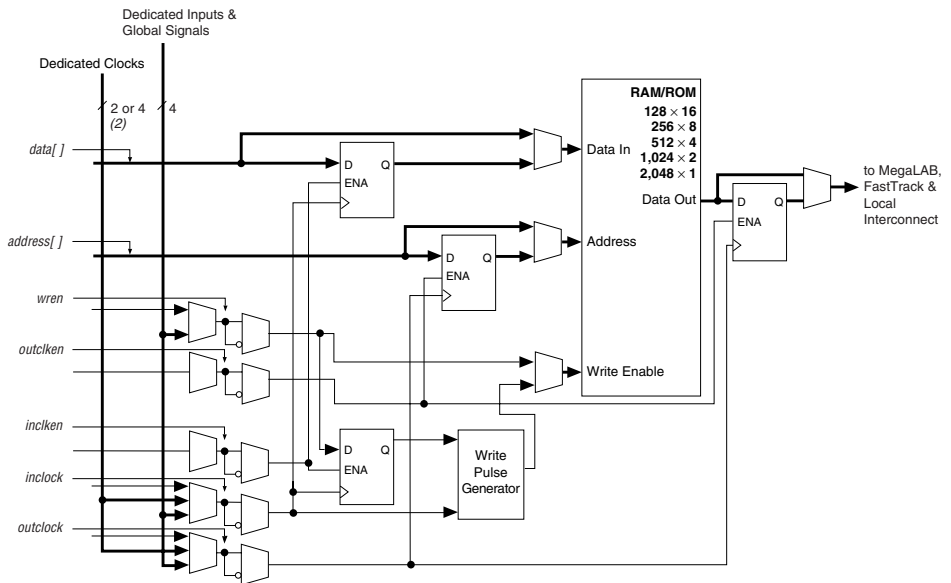
### Macrocells

APEX 20K macrocells can be configured individually for either sequential or combinatorial logic operation. The macrocell consists of three functional blocks: the logic array, the product-term select matrix, and the programmable register.

Combinatorial logic is implemented in the product terms. The product-term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as parallel expanders to be used to increase the logic available to another macrocell. One product term can be inverted; the Quartus II software uses this feature to perform DeMorgan's inversion for more efficient implementation of wide OR functions. The Quartus II software Compiler can use a NOT-gate push-back technique to emulate an asynchronous preset. Figure 14 shows the APEX 20K macrocell.



Figure 22. ESB in Single-Port Mode *Note (1)*



**Notes to Figure 22:**

- (1) All registers can be asynchronously cleared by ESB local interconnect signals, global signals, or the chip-wide reset.
- (2) APEX 20KE devices have four dedicated clocks.

**Content-Addressable Memory**

In APEX 20KE devices, the ESB can implement CAM. CAM can be thought of as the inverse of RAM. When read, RAM outputs the data for a given address. Conversely, CAM outputs an address for a given data word. For example, if the data FA12 is stored in address 14, the CAM outputs 14 when FA12 is driven into it.

CAM is used for high-speed search operations. When searching for data within a RAM block, the search is performed serially. Thus, finding a particular data word can take many cycles. CAM searches all addresses in parallel and outputs the address storing a particular word. When a match is found, a match flag is set high. Figure 23 shows the CAM block diagram.

APEX 20KE devices include an enhanced IOE, which drives the FastRow interconnect. The FastRow interconnect connects a column I/O pin directly to the LAB local interconnect within two MegaLAB structures. This feature provides fast setup times for pins that drive high fan-outs with complex logic, such as PCI designs. For fast bidirectional I/O timing, LE registers using local routing can improve setup times and OE timing. The APEX 20KE IOE also includes direct support for open-drain operation, giving faster clock-to-output for open-drain signals. Some programmable delays in the APEX 20KE IOE offer multiple levels of delay to fine-tune setup and hold time requirements. The Quartus II software compiler can set these delays automatically to minimize setup time while providing a zero hold time.

**Table 11** describes the APEX 20KE programmable delays and their logic options in the Quartus II software.

<b>Table 11. APEX 20KE Programmable Delay Chains</b>	
<b>Programmable Delays</b>	<b>Quartus II Logic Option</b>
Input Pin to Core Delay	Decrease input delay to internal cells
Input Pin to Input Register Delay	Decrease input delay to input registers
Core to Output Register Delay	Decrease input delay to output register
Output Register $t_{CO}$ Delay	Increase delay to output pin
Clock Enable Delay	Increase clock enable delay

The register in the APEX 20KE IOE can be programmed to power-up high or low after configuration is complete. If it is programmed to power-up low, an asynchronous clear can control the register. If it is programmed to power-up high, an asynchronous preset can control the register. **Figure 26** shows how fast bidirectional I/O pins are implemented in APEX 20KE devices. This feature is useful for cases where the APEX 20KE device controls an active-low input or another device; it prevents inadvertent activation of the input upon power-up.

## Advanced I/O Standard Support

APEX 20KE IOEs support the following I/O standards: LVTTTL, LVCMOS, 1.8-V I/O, 2.5-V I/O, 3.3-V PCI, PCI-X, 3.3-V AGP, LVDS, LVPECL, GTL+, CTT, HSTL Class I, SSTL-3 Class I and II, and SSTL-2 Class I and II.



For more information on I/O standards supported by APEX 20KE devices, see *Application Note 117 (Using Selectable I/O Standards in Altera Devices)*.

The APEX 20KE device contains eight I/O banks. In QFP packages, the banks are linked to form four I/O banks. The I/O banks directly support all standards except LVDS and LVPECL. All I/O banks can support LVDS and LVPECL with the addition of external resistors. In addition, one block within a bank contains circuitry to support high-speed True-LVDS and LVPECL inputs, and another block within a particular bank supports high-speed True-LVDS and LVPECL outputs. The LVDS blocks support all of the I/O standards. Each I/O bank has its own VCCIO pins. A single device can support 1.8-V, 2.5-V, and 3.3-V interfaces; each bank can support a different standard independently. Each bank can also use a separate  $V_{REF}$  level so that each bank can support any of the terminated standards (such as SSTL-3) independently. Within a bank, any one of the terminated standards can be supported. EP20K300E and larger APEX 20KE devices support the LVDS interface for data pins (smaller devices support LVDS clock pins, but not data pins). All EP20K300E and larger devices support the LVDS interface for data pins up to 155 Mbit per channel; EP20K400E devices and larger with an X-suffix on the ordering code add a serializer/deserializer circuit and PLL for higher-speed support.

Each bank can support multiple standards with the same VCCIO for output pins. Each bank can support one voltage-referenced I/O standard, but it can support multiple I/O standards with the same VCCIO voltage level. For example, when VCCIO is 3.3 V, a bank can support LVTTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

When the LVDS banks are not used as LVDS I/O banks, they support all of the other I/O standards. [Figure 29](#) shows the arrangement of the APEX 20KE I/O banks.

For designs that require both a multiplied and non-multiplied clock, the clock trace on the board can be connected to CLK2p. Table 14 shows the combinations supported by the ClockLock and ClockBoost circuitry. The CLK2p pin can feed both the ClockLock and ClockBoost circuitry in the APEX 20K device. However, when both circuits are used, the other clock pin (CLK1p) cannot be used.

**Table 14. Multiplication Factor Combinations**

Clock 1	Clock 2
×1	×1
×1, ×2	×2
×1, ×2, ×4	×4

## APEX 20KE ClockLock Feature

APEX 20KE devices include an enhanced ClockLock feature set. These devices include up to four PLLs, which can be used independently. Two PLLs are designed for either general-purpose use or LVDS use (on devices that support LVDS I/O pins). The remaining two PLLs are designed for general-purpose use. The EP20K200E and smaller devices have two PLLs; the EP20K300E and larger devices have four PLLs.

The following sections describe some of the features offered by the APEX 20KE PLLs.

### External PLL Feedback

The ClockLock circuit's output can be driven off-chip to clock other devices in the system; further, the feedback loop of the PLL can be routed off-chip. This feature allows the designer to exercise fine control over the I/O interface between the APEX 20KE device and another high-speed device, such as SDRAM.

### Clock Multiplication

The APEX 20KE ClockBoost circuit can multiply or divide clocks by a programmable number. The clock can be multiplied by  $m/(n \times k)$  or  $m/(n \times v)$ , where  $m$  and  $k$  range from 2 to 160, and  $n$  and  $v$  range from 1 to 16. Clock multiplication and division can be used for time-domain multiplexing and other functions, which can reduce design LE requirements.

**Table 24. APEX 20K 5.0-V Tolerant Device Recommended Operating Conditions** *Note (2)*

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CCINT}$	Supply voltage for internal logic and input buffers	(4), (5)	2.375 (2.375)	2.625 (2.625)	V
$V_{CCIO}$	Supply voltage for output buffers, 3.3-V operation	(4), (5)	3.00 (3.00)	3.60 (3.60)	V
	Supply voltage for output buffers, 2.5-V operation	(4), (5)	2.375 (2.375)	2.625 (2.625)	V
$V_I$	Input voltage	(3), (6)	-0.5	5.75	V
$V_O$	Output voltage		0	$V_{CCIO}$	V
$T_J$	Junction temperature	For commercial use	0	85	°C
		For industrial use	-40	100	°C
$t_R$	Input rise time			40	ns
$t_F$	Input fall time			40	ns

**Table 25. APEX 20K 5.0-V Tolerant Device DC Operating Conditions (Part 1 of 2)** *Notes (2), (7), (8)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IH}$	High-level input voltage		1.7, $0.5 \times V_{CCIO}$ (9)		5.75	V
$V_{IL}$	Low-level input voltage		-0.5		$0.8, 0.3 \times V_{CCIO}$ (9)	V
$V_{OH}$	3.3-V high-level TTL output voltage	$I_{OH} = -8$ mA DC, $V_{CCIO} = 3.00$ V (10)	2.4			V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 3.00$ V (10)	$V_{CCIO} - 0.2$			V
	3.3-V high-level PCI output voltage	$I_{OH} = -0.5$ mA DC, $V_{CCIO} = 3.00$ to $3.60$ V (10)	$0.9 \times V_{CCIO}$			V
	2.5-V high-level output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 2.30$ V (10)	2.1			V
		$I_{OH} = -1$ mA DC, $V_{CCIO} = 2.30$ V (10)	2.0			V
		$I_{OH} = -2$ mA DC, $V_{CCIO} = 2.30$ V (10)	1.7			V

**Table 25. APEX 20K 5.0-V Tolerant Device DC Operating Conditions (Part 2 of 2)** Notes (2), (7), (8)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{OL}$	3.3-V low-level TTL output voltage	$I_{OL} = 12 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (11)			0.45	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (11)			0.2	V
	3.3-V low-level PCI output voltage	$I_{OL} = 1.5 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ to } 3.60 \text{ V}$ (11)			$0.1 \times V_{CCIO}$	V
	2.5-V low-level output voltage	$I_{OL} = 0.1 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (11)			0.2	V
		$I_{OL} = 1 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (11)			0.4	V
		$I_{OL} = 2 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (11)			0.7	V
$I_I$	Input pin leakage current	$V_I = 5.75 \text{ to } -0.5 \text{ V}$	-10		10	$\mu\text{A}$
$I_{OZ}$	Tri-stated I/O pin leakage current	$V_O = 5.75 \text{ to } -0.5 \text{ V}$	-10		10	$\mu\text{A}$
$I_{CC0}$	$V_{CC}$ supply current (standby) (All ESBs in power-down mode)	$V_I = \text{ground}$ , no load, no toggling inputs, -1 speed grade (12)		10		mA
		$V_I = \text{ground}$ , no load, no toggling inputs, -2, -3 speed grades (12)		5		mA
$R_{CONF}$	Value of I/O pin pull-up resistor before and during configuration	$V_{CCIO} = 3.0 \text{ V}$ (13)	20		50	W
		$V_{CCIO} = 2.375 \text{ V}$ (13)	30		80	W

**Table 29. APEX 20KE Device DC Operating Conditions** *Notes (7), (8), (9)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IH}$	High-level LVTTL, CMOS, or 3.3-V PCI input voltage		1.7, $0.5 \times V_{CCIO}$ (10)		4.1	V
$V_{IL}$	Low-level LVTTL, CMOS, or 3.3-V PCI input voltage		-0.5		$0.8, 0.3 \times V_{CCIO}$ (10)	V
$V_{OH}$	3.3-V high-level LVTTL output voltage	$I_{OH} = -12$ mA DC, $V_{CCIO} = 3.00$ V (11)	2.4			V
	3.3-V high-level LVCMOS output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 3.00$ V (11)	$V_{CCIO} - 0.2$			V
	3.3-V high-level PCI output voltage	$I_{OH} = -0.5$ mA DC, $V_{CCIO} = 3.00$ to $3.60$ V (11)	$0.9 \times V_{CCIO}$			V
	2.5-V high-level output voltage	$I_{OH} = -0.1$ mA DC, $V_{CCIO} = 2.30$ V (11)	2.1			V
		$I_{OH} = -1$ mA DC, $V_{CCIO} = 2.30$ V (11)	2.0			V
		$I_{OH} = -2$ mA DC, $V_{CCIO} = 2.30$ V (11)	1.7			V
$V_{OL}$	3.3-V low-level LVTTL output voltage	$I_{OL} = 12$ mA DC, $V_{CCIO} = 3.00$ V (12)			0.4	V
	3.3-V low-level LVCMOS output voltage	$I_{OL} = 0.1$ mA DC, $V_{CCIO} = 3.00$ V (12)			0.2	V
	3.3-V low-level PCI output voltage	$I_{OL} = 1.5$ mA DC, $V_{CCIO} = 3.00$ to $3.60$ V (12)			$0.1 \times V_{CCIO}$	V
	2.5-V low-level output voltage	$I_{OL} = 0.1$ mA DC, $V_{CCIO} = 2.30$ V (12)			0.2	V
		$I_{OL} = 1$ mA DC, $V_{CCIO} = 2.30$ V (12)			0.4	V
		$I_{OL} = 2$ mA DC, $V_{CCIO} = 2.30$ V (12)			0.7	V
$I_I$	Input pin leakage current	$V_I = 4.1$ to $-0.5$ V (13)	-10		10	$\mu$ A
$I_{OZ}$	Tri-stated I/O pin leakage current	$V_O = 4.1$ to $-0.5$ V (13)	-10		10	$\mu$ A
$I_{CC0}$	$V_{CC}$ supply current (standby) (All ESBs in power-down mode)	$V_I =$ ground, no load, no toggling inputs, -1 speed grade		10		mA
		$V_I =$ ground, no load, no toggling inputs, -2, -3 speed grades		5		mA
$R_{CONF}$	Value of I/O pin pull-up resistor before and during configuration	$V_{CCIO} = 3.0$ V (14)	20		50	k $\Omega$
		$V_{CCIO} = 2.375$ V (14)	30		80	k $\Omega$
		$V_{CCIO} = 1.71$ V (14)	60		150	k $\Omega$

**Figure 39. ESB Synchronous Timing Waveforms**

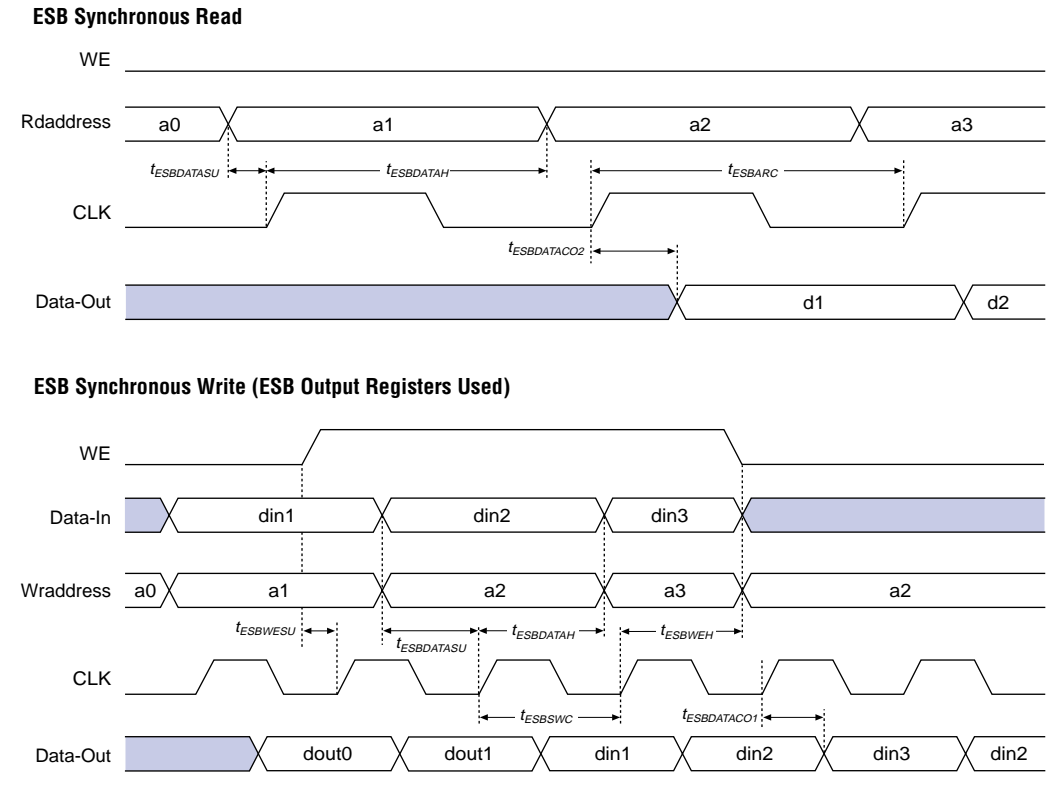


Figure 40 shows the timing model for bidirectional I/O pin timing.



**Table 39. APEX 20KE External Bidirectional Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions
$t_{\text{INSUBIDIR}}$	Setup time for bidirectional pins with global clock at LAB adjacent Input Register	
$t_{\text{INHBDIR}}$	Hold time for bidirectional pins with global clock at LAB adjacent Input Register	
$t_{\text{OUTCOBIDIR}}$	Clock-to-output delay for bidirectional pins with global clock at IOE output register	C1 = 10 pF
$t_{\text{XZBIDIR}}$	Synchronous Output Enable Register to output buffer disable delay	C1 = 10 pF
$t_{\text{ZXBIDIR}}$	Synchronous Output Enable Register output buffer enable delay	C1 = 10 pF
$t_{\text{INSUBIDIRPLL}}$	Setup time for bidirectional pins with PLL clock at LAB adjacent Input Register	
$t_{\text{INHBDIRPLL}}$	Hold time for bidirectional pins with PLL clock at LAB adjacent Input Register	
$t_{\text{OUTCOBIDIRPLL}}$	Clock-to-output delay for bidirectional pins with PLL clock at IOE output register	C1 = 10 pF
$t_{\text{XZBIDIRPLL}}$	Synchronous Output Enable Register to output buffer disable delay with PLL	C1 = 10 pF
$t_{\text{ZXBIDIRPLL}}$	Synchronous Output Enable Register output buffer enable delay with PLL	C1 = 10 pF

**Note to Tables 38 and 39:**

(1) These timing parameters are sample-tested only.

**Table 46. EP20K200 External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}$ (1)	1.9		2.3		2.6		ns
$t_{\text{INHBIDIR}}$ (1)	0.0		0.0		0.0		ns
$t_{\text{OUTCOBIDIR}}$ (1)	2.0	4.6	2.0	5.6	2.0	6.8	ns
$t_{\text{XZBIDIR}}$ (1)		5.0		5.9		6.9	ns
$t_{\text{ZXBIDIR}}$ (1)		5.0		5.9		6.9	ns
$t_{\text{INSUBIDIR}}$ (2)	1.1		1.2		—		ns
$t_{\text{INHBIDIR}}$ (2)	0.0		0.0		—		ns
$t_{\text{OUTCOBIDIR}}$ (2)	0.5	2.7	0.5	3.1	—	—	ns
$t_{\text{XZBIDIR}}$ (2)		4.3		5.0		—	ns
$t_{\text{ZXBIDIR}}$ (2)		4.3		5.0		—	ns

**Table 47. EP20K400 External Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSU}}$ (1)	1.4		1.8		2.0		ns
$t_{\text{INH}}$ (1)	0.0		0.0		0.0		ns
$t_{\text{OUTCO}}$ (1)	2.0	4.9	2.0	6.1	2.0	7.0	ns
$t_{\text{INSU}}$ (2)	0.4		1.0		—		ns
$t_{\text{INH}}$ (2)	0.0		0.0		—		ns
$t_{\text{OUTCO}}$ (2)	0.5	3.1	0.5	4.1	—	—	ns

**Table 48. EP20K400 External Bidirectional Timing Parameters**

Symbol	-1 Speed Grade		-2 Speed Grade		-3 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}$ (1)	1.4		1.8		2.0		ns
$t_{\text{INHBIDIR}}$ (1)	0.0		0.0		0.0		ns
$t_{\text{OUTCOBIDIR}}$ (1)	2.0	4.9	2.0	6.1	2.0	7.0	ns
$t_{\text{XZBIDIR}}$ (1)		7.3		8.9		10.3	ns
$t_{\text{ZXBIDIR}}$ (1)		7.3		8.9		10.3	ns
$t_{\text{INSUBIDIR}}$ (2)	0.5		1.0		—		ns
$t_{\text{INHBIDIR}}$ (2)	0.0		0.0		—		ns
$t_{\text{OUTCOBIDIR}}$ (2)	0.5	3.1	0.5	4.1	—	—	ns
$t_{\text{XZBIDIR}}$ (2)		6.2		7.6		—	ns
$t_{\text{ZXBIDIR}}$ (2)		6.2		7.6		—	ns

**Table 69. EP20K160E  $t_{MAX}$  Routing Delays**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{F1-4}$		0.25		0.26		0.28	ns
$t_{F5-20}$		1.00		1.18		1.35	ns
$t_{F20+}$		1.95		2.19		2.30	ns

**Table 70. EP20K160E Minimum Pulse Width Timing Parameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{CH}$	1.34		1.43		1.55		ns
$t_{CL}$	1.34		1.43		1.55		ns
$t_{CLRP}$	0.18		0.19		0.21		ns
$t_{PREP}$	0.18		0.19		0.21		ns
$t_{ESBCH}$	1.34		1.43		1.55		ns
$t_{ESBCL}$	1.34		1.43		1.55		ns
$t_{ESBWP}$	1.15		1.45		1.73		ns
$t_{ESBRP}$	0.93		1.15		1.38		ns

**Table 71. EP20K160E External Timing Parameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{INSU}$	2.23		2.34		2.47		ns
$t_{INH}$	0.00		0.00		0.00		ns
$t_{OUTCO}$	2.00	5.07	2.00	5.59	2.00	6.13	ns
$t_{INSUPLL}$	2.12		2.07		-		ns
$t_{INHPLL}$	0.00		0.00		-		ns
$t_{OUTCOPLL}$	0.50	3.00	0.50	3.35	-	-	ns

**Table 72. EP20K160E External Bidirectional Timing Parameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{INSUBIDIR}}$	2.86		3.24		3.54		ns
$t_{\text{INHBIDIR}}$	0.00		0.00		0.00		ns
$t_{\text{OUTCOBIDIR}}$	2.00	5.07	2.00	5.59	2.00	6.13	ns
$t_{\text{XZBIDIR}}$		7.43		8.23		8.58	ns
$t_{\text{ZXBIDIR}}$		7.43		8.23		8.58	ns
$t_{\text{INSUBIDIRPLL}}$	4.93		5.48		-		ns
$t_{\text{INHBIDIRPLL}}$	0.00		0.00		-		ns
$t_{\text{OUTCOBIDIRPLL}}$	0.50	3.00	0.50	3.35	-	-	ns
$t_{\text{XZBIDIRPLL}}$		5.36		5.99		-	ns
$t_{\text{ZXBIDIRPLL}}$		5.36		5.99		-	ns

Tables 73 through 78 describe  $f_{\text{MAX}}$  LE Timing Microparameters,  $f_{\text{MAX}}$  ESB Timing Microparameters,  $f_{\text{MAX}}$  Routing Delays, Minimum Pulse Width Timing Parameters, External Timing Parameters, and External Bidirectional Timing Parameters for EP20K200E APEX 20KE devices.

**Table 73. EP20K200E  $f_{\text{MAX}}$  LE Timing Microparameters**

Symbol	-1		-2		-3		Unit
	Min	Max	Min	Max	Min	Max	
$t_{\text{SU}}$	0.23		0.24		0.26		ns
$t_{\text{H}}$	0.23		0.24		0.26		ns
$t_{\text{CO}}$		0.26		0.31		0.36	ns
$t_{\text{LUT}}$		0.70		0.90		1.14	ns

## Revision History

The information contained in the *APEX 20K Programmable Logic Device Family Data Sheet* version 5.1 supersedes information published in previous versions.

### Version 5.1

*APEX 20K Programmable Logic Device Family Data Sheet* version 5.1 contains the following changes:

- In version 5.0, the VI input voltage spec was updated in Table 28 on page 63.
- In version 5.0, *Note (5)* to Tables 27 through 30 was revised.
- Added *Note (2)* to Figure 21 on page 33.

### Version 5.0

*APEX 20K Programmable Logic Device Family Data Sheet* version 5.0 contains the following changes:

- Updated Tables 23 through 26. Removed 2.5-V operating condition tables because all APEX 20K devices are now 5.0-V tolerant.
- Updated conditions in Tables 33, 38 and 39.
- Updated data for  $t_{ESB\text{DATAH}}$  parameter.

### Version 4.3

*APEX 20K Programmable Logic Device Family Data Sheet* version 4.3 contains the following changes:

- Updated Figure 20.
- Updated *Note (2)* to Table 13.
- Updated notes to Tables 27 through 30.

### Version 4.2

*APEX 20K Programmable Logic Device Family Data Sheet* version 4.2 contains the following changes:

- Updated Figure 29.
- Updated *Note (1)* to Figure 29.